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Packet No.: 52775-024

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of : Customer Number: 20277  
Masahiro NAKAYAMA, et al. : Confirmation Number: 1716  
Serial No.: 10/662,524 : Group Art Unit: 2826  
Filed: September 16, 2003 : Examiner: not yet assigned  
For: CHAMFERED FREESTANDING NITRIDE SEMICONDUCTOR WAFER AND  
METHOD OF CHAMFERING NITRIDE SEMICONDUCTOR WAFER

**INFORMATION DISCLOSURE STATEMENT**

Mail Stop Amendments  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

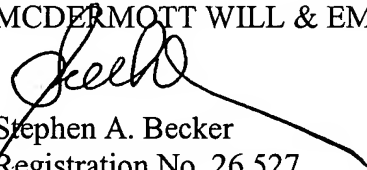
Each non-English language reference was first cited in a corresponding foreign application search report or office action and its relevance discussed therein. A copy of the foreign search report or office action, is attached for the Examiner's information.

10/662,524

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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## INFORMATION DISCLOSURE CITATION IN AN APPLICATION

ATTY. DOCKET NO.  
52775-024

SERIAL NO.  
10/662,524

APPLICANT  
**Masahiro NAKAYAMA, et al.**

**FILING DATE**  
**September 16, 2003**

**GROUP  
2826**

## U.S. PATENT DOCUMENTS

[illegible]

## FOREIGN PATENT DOCUMENTS

| EXAMINER'S INITIALS | CITE NO. | Foreign Patent Document<br>Country Codes - Number - Kind<br>Codes (if known) | Publication Date<br>MM-DD-YYYY | Name of Patentee or<br>Applicant of Cited Document | Pages, Columns, Lines<br>Where Relevant<br>Figures Appear | Translation |    |
|---------------------|----------|--|--------------------------------|--|---|-------------|----|
|                     |          |  |                                |  |   | Yes         | No |
|                     | A1       | EP 1 034 883   | 09/13/2000                     | Nippei Toyama Corp.                                |   | Yes         | No |
|                     | A2       | EP 1 120 191   | 08/01/2001                     | TSK America, Inc.                                  |   |             |    |
|                     |          |  |                                |  |   |             |    |
|                     |          |  |                                |  |   |             |    |
|                     |          |  |                                |  |   |             |    |
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

| EXAMINER'S INITIALS | CITE NO. | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. |  |
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EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.